

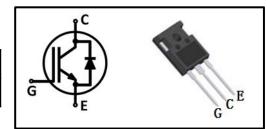
Features

- Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}
- Low V_{CEsat}, fast switching
- High ruggedness, good thermal stability
- Very tight parameter distribution

Туре	Marking	Package Code
MPBW25N120BF	MP25N120BF	TO-247-3

Applications

- **■** Frequency converter
- UPS



Maximum Rated Values

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V _{CE}	1200	V
DC collector current, limited by T_{jmax} T_{C} =25°C T_{C} =100°C	I _C	50 25	
Pulsed collector current, t _p limited by T _{jmax} 1)	I _{Cpuls}	100	A
Diode forward current, limited by T_{jmax} T_{C} =25°C T_{C} =100°C	I _F	50 25	
Diode pulsed current, t _p limited by T _{jmax} 1)	I _{Fpuls}	100	
Gate-emitter voltage		±20	V
Transient Gate-emitter voltage (t _p ≤10us,D<0.01)	V_{GE}	±30	V
Short circuit withstand time V_{GE} =15V, V_{CC} =600V, T_{j} ≤175°C Allowed number of short circuits < 1000 Time between short circuits: ≥ 1.0s	t _{sc}	10	μs
Power dissipation T _C =25°C	В	348	W
Power dissipation T _C =100°C	P _{tot}	174] vv
Operating junction temperature	T _j	-40~175	
Storage temperature	T _{stg}	-55~150	_℃
Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s		260	
Mounting torque, M3 screw Maximum of mounting processes: 3	М	0.6	Nm

¹⁾ Defined by design. Not subject to production test.



Thermal Characteristics

Parameter	Symbol	Min	Тур	Max	Unit
IGBT thermal resistance, junction-case	R _{thJC}	1	1	0.43	
Diode thermal resistance, junction-case	R _{thJCD}	-	-	0.80	K/W
Thermal Resistance, junction-ambient	R _{thJA}	-	-	40	

Electrical Characteristics (at T_j =25°C, unless otherwise specified) Static Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V, I _C =0.25mA	1200	-	-	
Collector-emitter		V _{GE} =15V, I _C =25A T _j =25℃	-	1.9	2.4	
saturation voltage	V _{CE(sat)}	T _j =150°C	-	2.5	-	
		T _j =175°C	1	2.6	-	V
	V _F	V _{GE} =0V, I _F =25A T _j =25°C	ı	2.2	-	
Diode forward voltage		T _j =150°C	ı	1.7	-	
		T _j =175°C	-	1.6	-	
G-E threshold voltage	$V_{GE(th)}$	I _C =1mA, V _{CE} =V _{GE}	5.5	6.0	6.5	
C-E leakage current	I _{CES}	V_{CE} =1200V, V_{GE} =0V T_{j} =25°C	-	-	0.1	mA
		T _j =175°C	-	-	4.0	
G-E leakage current	I _{GES}	V _{CE} =0V, V _{GE} =20V	-	-	200	nA
Transconductance	g _{fs}	V _{CE} =20V, I _C =25A	-	15	-	S

Dynamic Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Input capacitance	C _{ies}	\/ -25\/	-	1767	-	
Output capacitance	C _{oes}	V _{CE} =25V, V _{GE} =0V, f=1MHz	-	116	-	pF
Reverse transfer capacitance	C _{res}		-	62	-	'
Gate charge	Q_G	V _{CC} =960V, I _C =25A, V _{GE} =15V	1	171	1	nC
Short circuit collector current	I _{C(SC)}	V _{GE} =15V, V _{CC} ≤600V, t _{SC} ≤10μs, T _j =175°C	-	90	-	А



IGBT Switching Characteristics

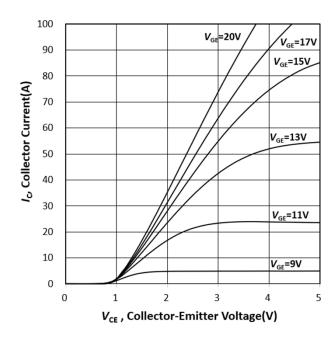
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Turn-on delay time	t _{d(on)}		-	32	-	
Rise time	t _r] T _i =25℃,	-	52	-	
Turn-off delay time	t _{d(off)}	V _{CC} =600V,	-	266	-	ns
Fall time	t _f	I _C =25A, V _{GE} =0/15V,	-	246	-	
Turn-on energy	E _{on}	$R_{G}=16\Omega$,	-	1.6	-	
Turn-off energy	E _{off}	Inductive load	-	1.9	-	mJ
Total switching energy	E _{ts}		-	3.5	-	
Turn-on delay time	t _{d(on)}		-	30	-	
Rise time	t _r] T _i =175°C,	-	50	-	
Turn-off delay time	t _{d(off)}	$V_{CC} = 600V$	-	322	-	ns
Fall time	t _f	I _C =25A, V _{GE} =0/15V,	-	378	-	
Turn-on energy	E _{on}	$R_{G}=16\Omega$,	-	1.7	-	
Turn-off energy	E _{off}	Inductive load	-	2.5	_	mJ
Total switching energy	E _{ts}]	-	4.2	-	

Diode Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Diode reverse recovery time	t _{rr}	T _i =25°C,	-	256	-	ns
Diode reverse recovery charge	Q _{rr}	√ _R =600V, I _F =25A,	-	1.35	-	μC
Diode peak reverse recovery current	I _{rrm}	di _F /dt=400A/µs	-	12.4	-	А
Diode reverse recovery time	t _{rr}	T _i =175°C,	-	350	-	ns
Diode reverse recovery charge	Q _{rr}	∫ V _R =600V, I _F =25A,	-	4.28	-	μC
Diode peak reverse recovery current	I _{rrm}	di _F /dt=400A/µs	-	26.2	-	Α

V_{GE}=20V





(V_{GE}=15V)

V_{GE}=15V

V_{GE}=13V

V_{GE}=11V

V_{GE}=11V

V_{GE}=9V

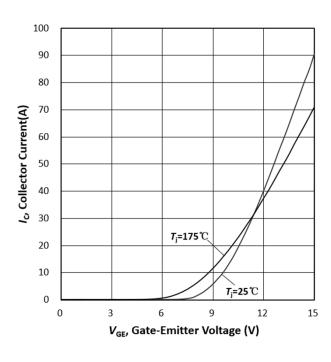
V_{CE}, Collector-Emitter Voltage(V)

80

70

Figure 1. Typical output characteristic $(T_i = 25 \text{ °C})$

Figure 2. Typical output characteristic $(T_i = 175^{\circ}C)$



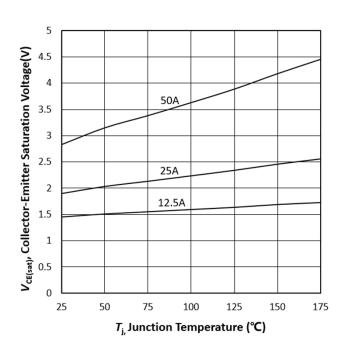


Figure 3. Typical transfer characteristic $(V_{CE}=25V)$

Figure 4. Typical collector-emitter saturation voltage as a function of junction temperature $(V_{GE}=15V)$



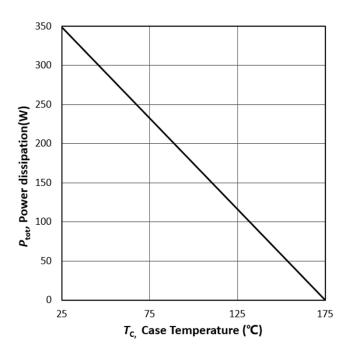


Figure 5. Power dissipation as a function of case temperature $(T_i \le 175^{\circ}\text{C})$

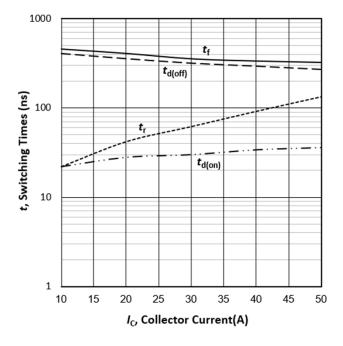


Figure 7. Typical switching times as a function of collector current (inductive load, T_j =175°C, V_{CE} =600V, V_{GE} =0/15V, R_G =16 Ω , Dynamic test circuit in Figure E)

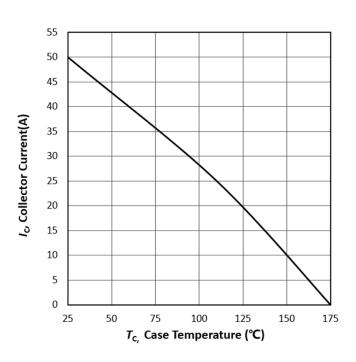


Figure 6. Collector current as a function of case temperature $(V_{GE} \ge 15V, T_i \le 175^{\circ}C)$

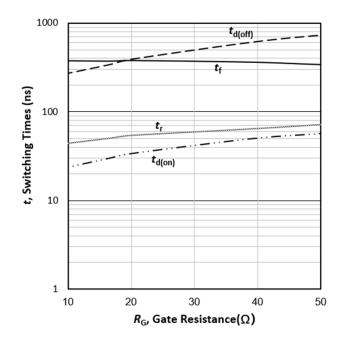


Figure 8. Typical switching times as a function of gate resistor (inductive load, T_j =175°C, V_{CE} =600V, V_{GE} =0/15V, I_{C} =25A, Dynamic test circuit in Figure E)



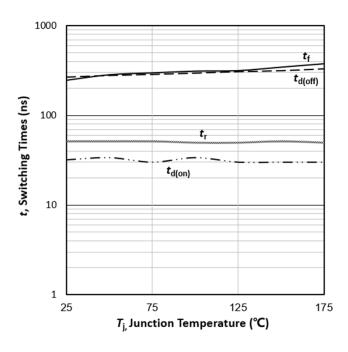


Figure 9. Typical switching times as a function of junction temperature (inductive load, $V_{\rm CE}$ =600V, $V_{\rm GE}$ =0/15V, $I_{\rm C}$ =25A, $R_{\rm G}$ =16 Ω , Dynamic test circuit in Figure E)

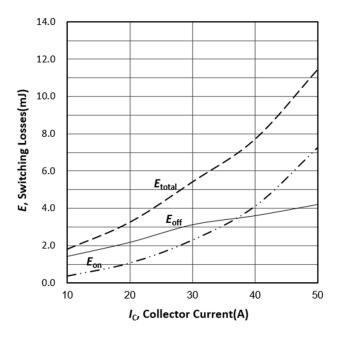


Figure 11. Typical switching energy losses as a function of collector current (inductive load, T_j =175°C, V_{CE} =600V, V_{GE} =0/15V, R_G =16 Ω , Dynamic test circuit in Figure E)

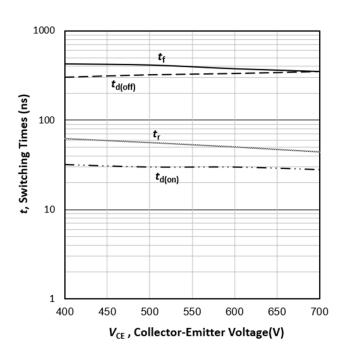


Figure 10. Typical switching times as a function of collector emitter voltage (inductive load, T_j =175°C, V_{GE} =0/15V, I_{C} =25A, R_{G} =16 Ω , Dynamic test circuit in Figure E)

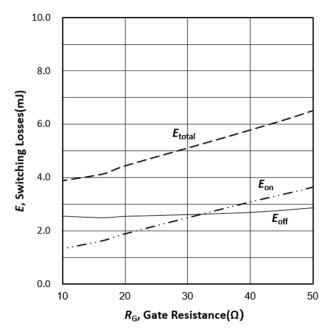


Figure 12. Typical switching energy losses as a function of gate resistor (inductive load, T_j =175°C, V_{CE} =600V, V_{GE} =0/15V, I_{C} =25A, Dynamic test circuit in Figure E)



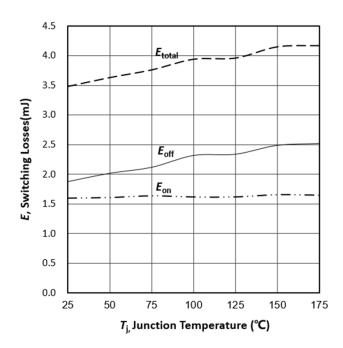


Figure 13. Typical switching energy losses as a function of junction temperature (inductive load, $V_{\rm CE}$ =600V, $V_{\rm GE}$ =0/15V, $I_{\rm C}$ =25A, $R_{\rm G}$ =16 Ω , Dynamic test circuit in Figure E)

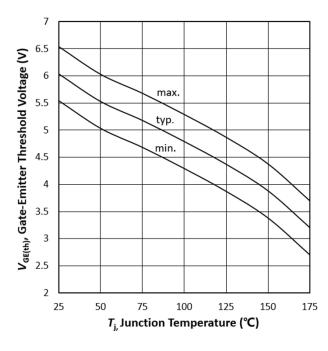


Figure 15. Gate-emitter threshold voltage as a function of junction temperature $(I_c=1\text{mA})$

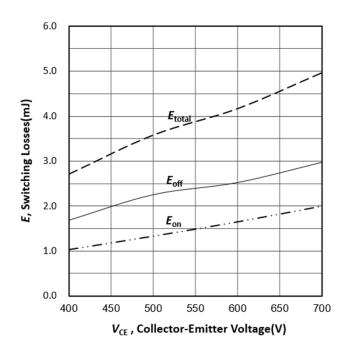


Figure 14. Typical switching energy losses as a function of collector emitter voltage (inductive load, T_j =175°C, V_{GE} =0/15V, I_C =25A, R_G =16 Ω , Dynamic test circuit in Figure E)

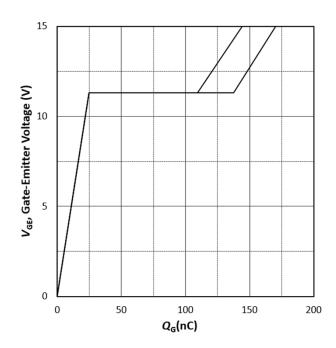


Figure 16. Typical gate charge $(I_c=25A)$



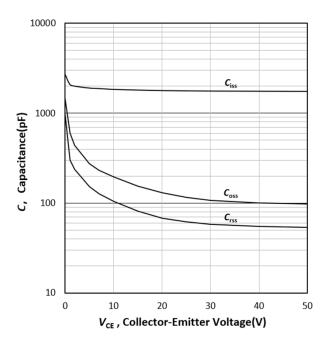


Figure 17. Typical capacitance as a function of collector-emitter voltage $(V_{GE}=0V, f=1MHz)$

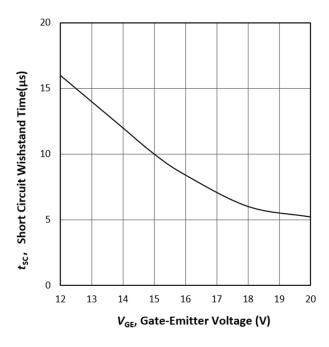


Figure 19. Typical short circuit withstand time as a function of gate emitter voltage $(V_{CE}=600\text{V}, \text{ start at } T_{\text{imax}} \leq 175 \, ^{\circ}\text{C})$

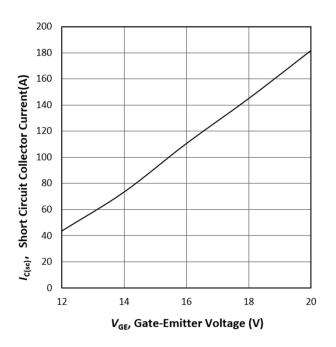


Figure 18. Typical short circuit collector current as a function of gate emitter voltage $(V_{CE} \le 600 \text{V}, T_i \le 175 \text{ °C})$

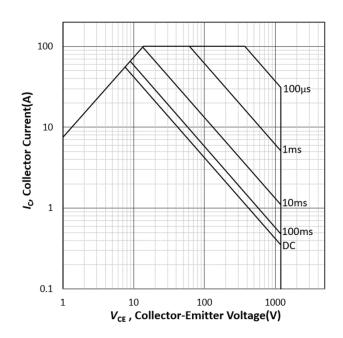


Figure 20. Forward Bias SOA (D=0, T_c =25 °C, T_j ≤175 °C, V_{GF} =15V)



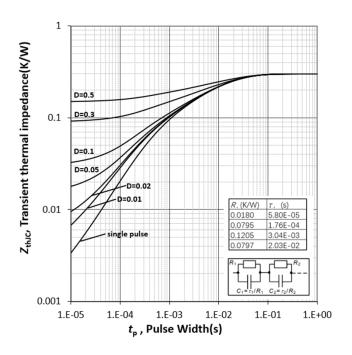


Figure 21. IGBT transient thermal impedance(typical) $(D=t_{\rm D}/T)$

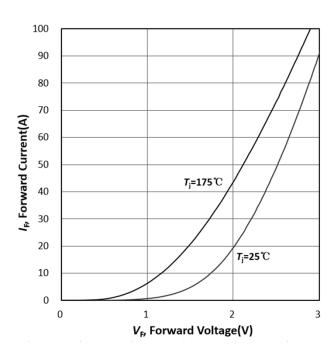


Figure 23. Typical diode forward current as a function of forward voltage

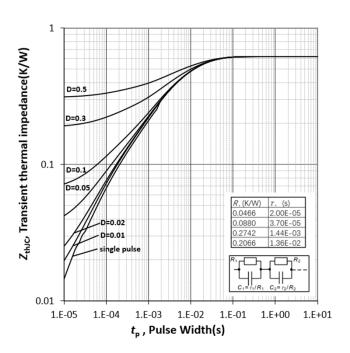


Figure 22. FRD transient thermal impedance(typical) $(D=t_o/T)$

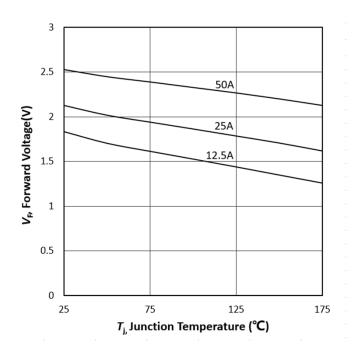


Figure 24. Typical diode forward voltage as a function of junction temperature



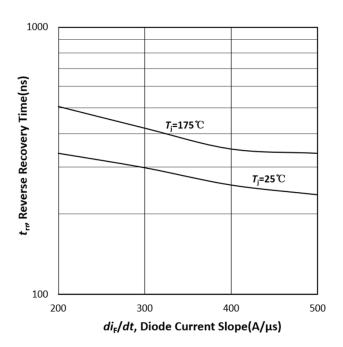


Figure 25. Typical reverse recovery time as a function of diode current slope $(V_R=600V, I_F=25A, Dynamic test circuit in Figure E)$

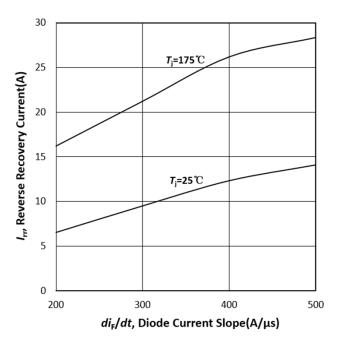


Figure 27. Typical reverse recovery current as a function of diode current slope $(V_R=600V, I_F=25A, Dynamic test circuit in Figure E)$

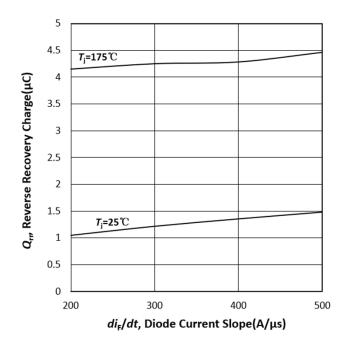


Figure 26. Typical reverse recovery charge as a function of diode current slope $(V_R=600V, I_F=25A, Dynamic test circuit in Figure E)$



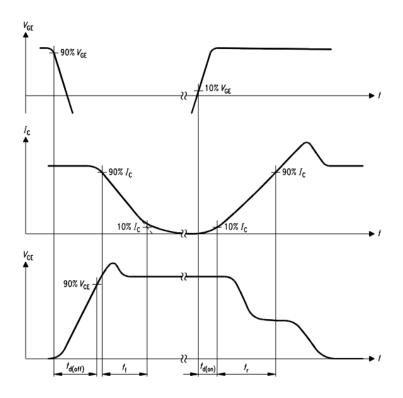


Figure A. Definition of switching times

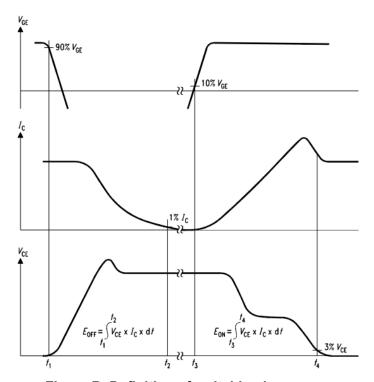


Figure B. Definition of switching losses

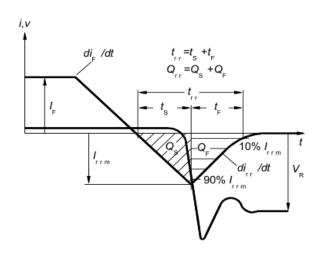


Figure C. Definition of diodes switching characteristics

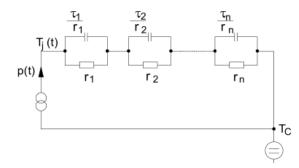


Figure D. Thermal equivalent circuit

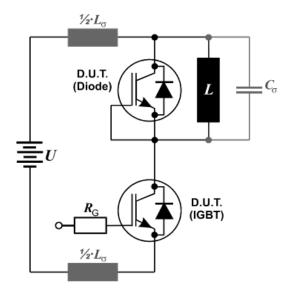
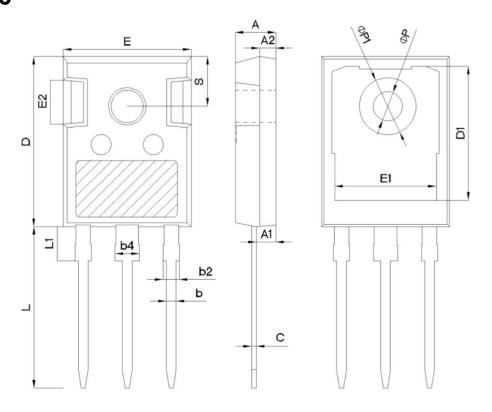


Figure E. Switching test circuit



TO-247-3



		mm		
SYMBOL	MIN	NOM	MAX	
A	4.80	5.00	5.20	
A1	2.21	2.41	2.61	
A2	1.85	2.00	2.15	
ь	1.11	1.21	1.36	
b2	1.91	2.01	2.21	
b4	2.91	3.01	3.21	
С	0.51	0.61	0.75	
D	20.70	21.00	21.30	
D1	16.25	16.55	16.85	
Е	15.50	15.80	16.10	
E1	13.00	13.30	13.60	
E2	4.80	5.00	5.20	
E3	2.30	2.50	2.70	
e		5.44BSC		
L	19.62	19.92	20.22	
L1	-	-	4.30	
ФР	3.40	3.60	3.80	
ФР1	-	-	7.30	
S	6.15BSC			



Revision History

Revision	Subjects (major changes since last revision)	Date
1.0	Initial version	2019.7
2.0	Add chart	2020.3
2.1	Update chart	2020.8

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